Search	Notes

ch Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/870,811	SMITH ET AL.	
	Examiner	Art Unit	
1.2011 2.212 1.012 1.000 1.001	Djenane M. Bayard	2141	

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Class	Subclass	Date	Examiner
707	6	5/31/2005	DB
709	203	5/31/2005	DB
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